



Sheet 1 of 1

Form PTO-1449 (REV. 8-83)		U.S. Department of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 109943		APPLICATION NO. 09/987,986	
INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Ana M. TESSADRO			
				FILING DATE November 16, 2001		Att. Jct: 2625	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
da	1.	5,212,740	05/1993	PAEK et al.	382	266	
	2.	5,561,724	10/1996	KIDO et al.		269	
	3.	5,563,962	10/1996	PETERS et al.		268	
	4.	5,671,294	09/1997	ROGERS et al.		228	
	5.	5,881,171	03/1999	KINJO		199	
	6.	6,111,983	08/2000	FENSTER et al.		203	
	7.	6,141,033	10/2000	MICHAEL et al.	348	25	
	8.	6,178,260	01/2001	LI et al.	382	173	
da	9.	6,192,150	02/2001	LEOW et al.	382	190	
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB CLASS	
OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)							
da	1.	S. Akoy, R. Haralick, "Feature Normalization and Likelihood-based Similarity Measures for Image Retrieval", 2000.					
da	2.	J. Bexdek et al., "FCM: The Fuzzy c-Means Clustering Algorithm", Computers and Geosciences, Vol. 10, NRO 2-3, pp 191-203					
da	3.	F. Farrokhnia, A. Jain, "A multi-Channel Filtering Approach to Texture Segmentation", 1991 IEEE Computer Society Conference on Comp. Vision and Pattern Recognition, Hawaii, June 3-6, 1991					
da	4.	K. Fukunaga, "Introduction to Statistical Pattern Recognition", Academic Press, 1990					
da	5.	A.K. Jain and F. Farrokhnia, "Unsupervised Texture Segmentation Using Gabor Filters", Pattern Recognition, Vol. 24, NRO 12, pp 1167-1186, 1991					
da	6.	Kenneth I. Laws, "Rapid Texture Identification", Image Processing for Missile Guidance, Vol 238, pp 376-380, 1980					
da	7.	Trygve Randen and John H. Husoy, "Filtering for Texture Classification: A Comparative Study", IEEE Transactions on Pattern Analysis and Machine Intelligence, Vol. 21, NO. 4, April 1999					
EXAMINER						DATE CONSIDERED 12-17-07	
Examiner: Initial if citation considered, whether or not citation is in conformance with M.P.E.P. 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Date: April 2, 2002



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INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)				APPLICANT Ana M. TESSADRO			
				FILING DATE November 16, 2001		Art Unit: 2621	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	
da	1.	5,212,740	05/1993	PAEK et al.	—	—	
	2.	5,561,724	10/1996	KIDO et al.	—	—	
	3.	5,563,962	10/1996	PETERS et al.	—	—	
	4.	5,671,294	09/1997	ROGERS et al.	—	—	
	5.	5,881,171	03/1999	KINJO	—	—	
	6.	6,111,983	08/2000	FENSTER et al.	—	—	
	7.	6,141,033	10/2000	MICHAEL et al.	—	—	
	8.	6,178,260	01/2001	LI et al.	—	—	
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Date: April 2, 2002